| Notice of References Cited | Notice | of References | Cited | |
|----------------------------|--------|---------------|-------|--|
|----------------------------|--------|---------------|-------|--|

| Application/Control No. 10/789,637 | Reexamination | Applicant(s)/Patent Under Reexamination SCHIECK ET AL. | | |
|---------------------------------------|---------------|--|--|--|
| Examiner | Art Unit | | | |
| KHANH B. DUONG | 2822 | Page 1 of 1 | | |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| * | Α | US-5,262,719 A | 11-1993 | Magdo, Steven | 324/158.1 |
| * | В | US-6,429,532 B1 | 08-2002 | Han et al. | 257/781 |
| * | С | US-6,933,524 B2 | 08-2005 | Hembree et al. | 257/48 |
| * | D | US-6,133,744 A | 10-2000 | Yojima et al. | 324/754 |
| * | Е | US-6,246,252 B1 | 06-2001 | Malladi et al. | 324/765 |
| * | F | US-6,590,294 B1 | 07-2003 | Lee et al. | 257/781 |
| * | G | US-5,834,844 A | 11-1998 | Akagawa et al. | 257/734 |
| * | Н | US-7,523,369 B2 | 04-2009 | Chang, Chih-Chung | 714/724 |
| * | Т | US-6,534,853 B2 | 03-2003 | Liu et al. | 257/692 |
| | J | US- | | | |
| | к | US- | | | |
| | L | US- | | | |
| | м | US- | | | |

FOREIGN PATENT DOCUMENTS

| | FOREIGN PATENT DOCUMENTS | | | | | |
|---|--------------------------|--|-----------------|---------|------|----------------|
| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
| | N | | | | | |
| | 0 | | | | | |
| | Р | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | s | | | | | |
| | Т | | | | | |

NON DATENT DOCUMENTS

| * | * Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | | | | | |
|---|---|--|--|--|--|--|
| | U | | | | | |
| | v | | | | | |
| | w | | | | | |
| | × | | | | | |

"A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.